Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/826,288	CHEN ET AL.	
Examiner	Art Unit	_
Ha T. Nouven	2812	

	SEARCHED		
Class	Subclass	Date	Examiner
	_		
<u> </u>			
			-

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
			<u></u>	
	1			

SEARCH N (INCLUDING SEAR))
	DATE	EXMR
EAST search (see printout)	12/11/2005	HN